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(54) **Title:** INTERFACE ELEMENT FOR A TESTING APPARATUS OF ELECTRONIC DEVICES AND CORRESPONDING MANUFACTURING METHOD

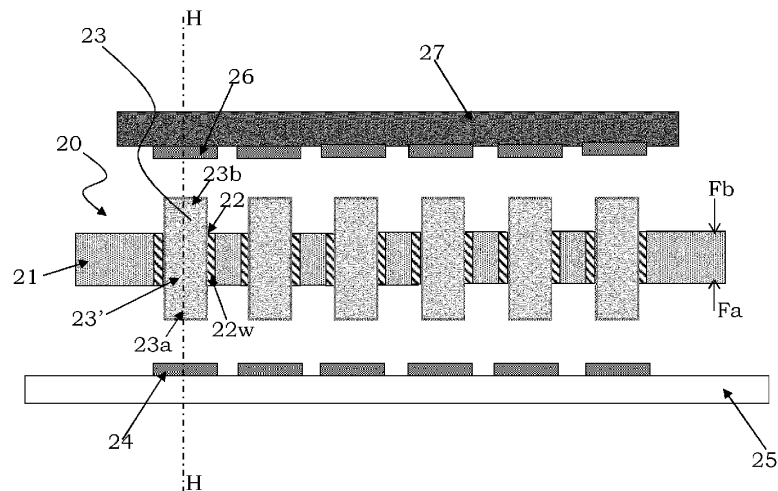


FIG. 2

(57) **Abstract:** An interface element (20) for a testing apparatus of electronic devices comprises at least one support (21) provided with a plurality of through-openings (22) that house respective interconnections elements (23), which extend between a first end (23a) and a second end (23b). Suitably, the interconnections elements (23) are made of a conductive elastomer that fills the openings (22) of the support (21), each of said interconnection elements (23) forming a conductive channel between different and opposing faces (Fa, Fb) of said support (21).

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